## General Description

The MAX5863 ultra-low-power, highly integrated analog front end is ideal for portable communication equipment such as handsets, PDAs, WLAN, and 3G wireless terminals. The MAX5863 integrates dual 8-bit receive ADCs and dual 10-bit transmit DACs while providing the highest dynamic performance at ultra-low power. The ADCs' analog I-Q input amplifiers are fully differential and accept 1VP-p full-scale signals. Typical I-Q channel phase matching is $\pm 0.03^{\circ}$ and amplitude matching is $\pm 0.03 \mathrm{~dB}$. The ADCs feature 48.5 dB SINAD and 69 dBc spurious-free dynamic range (SFDR) at $\mathrm{f} / \mathrm{N}=1.875 \mathrm{MHz}$ and f CLK $=7.5 \mathrm{Msps}$. The DACs' analog I -Q outputs are fully differential with $\pm 400 \mathrm{mV}$ full-scale output, and 1.4 V common-mode level. Typical I-Q channel phase match is $\pm 0.15^{\circ}$ and gain match is $\pm 0.05 \mathrm{~dB}$. The DACs also feature dual 10-bit resolution with 73 dBc SFDR, and 61 dB SNR at $\mathrm{fOUT}=620 \mathrm{kHz}$ and $\mathrm{fCLK}=7.5 \mathrm{MHz}$.
The ADCs and DACs operate simultaneously or independently for frequency-division duplex (FDD) and time-division duplex (TDD) modes. A 3-wire serial interface controls power-down and transceiver modes of operation. The typical operating power is 22.8 mW at $\mathrm{fCLK}=$ 7.5Msps with the ADCs and DACs operating simultaneously in transceiver mode. The MAX5863 features an internal 1.024 V voltage reference that is stable over the entire operating power-supply range and temperature range. The MAX5863 operates on a +2.7 V to +3.3 V analog power supply and $\mathrm{a}+1.8 \mathrm{~V}$ to +3.3 V digital I/O power supply for logic compatibility. The quiescent current is 3.5 mA in idle mode and $1 \mu \mathrm{~A}$ in shutdown mode. The MAX5863 is specified for the extended $\left(-40^{\circ} \mathrm{C}\right.$ to $\left.+85^{\circ} \mathrm{C}\right)$ temperature range and is available in a 48-pin thin QFN package.

## Applications

Narrowband/Wideband CDMA Handsets and PDAs
Fixed/Mobile Broadband Wireless Modems 3G Wireless Terminals

Ordering Information

| PART | TEMP RANGE | PIN-PACKAGE |
| :---: | :--- | :--- |
| MAX5863ETM | $-40^{\circ} \mathrm{C}$ to $+85^{\circ} \mathrm{C}$ | 48 Thin QFN-EP* <br> $(7 \mathrm{~mm} \times 7 \mathrm{~mm})$ |
| MAX5863E/D | $-40^{\circ} \mathrm{C}$ to $+85^{\circ} \mathrm{C}$ | Dice** |

*EP = Exposed paddle.
**Contact factory for dice specifications.
Pin Configuration appears at end of data sheet.

- Integrated Dual 8-Bit ADCs and Dual 10-Bit DACs
- Ultra-Low Power
22.8 mW at fCLK $=7.5 \mathrm{MHz}$ (Transceiver Mode) 20.7 mW at $\mathrm{fcLK}=5.2 \mathrm{MHz}$ (Transceiver Mode) Low-Current Idle and Shutdown Modes
- Excellent Dynamic Performance
48.5 dB SINAD at $\mathrm{f} \mathrm{N}=1.875 \mathrm{MHz}$ (ADC) 73 dBc SFDR at fout $=620 \mathrm{kHz}$ (DAC)
- Excellent Gain/Phase Match
$\pm 0.03^{\circ}$ Phase, $\pm 0.03 \mathrm{~dB}$ Gain at $\mathrm{f} / \mathrm{N}=1.875 \mathrm{MHz}$ (ADC)
- Internal/External Reference Option
- +1.8V to +3.3V Digital Output Level (TTL/CMOS Compatible)
- Multiplexed Parallel Digital Input/Output for ADCs/DACs
- Miniature 48-Pin Thin QFN Package ( $7 \mathrm{~mm} \times 7 \mathrm{~mm}$ )
- Evaluation Kit Available (Order MAX5865EVKIT)

Functional Diagram


# Ultra-Low-Power, High-Dynamic Performance, 7.5Msps Analog Front End 

## ABSOLUTE MAXIMUM RATINGS

| $V_{D D}$ to $G N D, V_{D D}$ to $O G N D$. GND to OGND. | $\begin{aligned} & . . . . . . .-0.3 \mathrm{~V} \text { to }+3.3 \mathrm{~V} \\ & \ldots . . . . .-0.3 \mathrm{~V} \text { to }+0.3 \mathrm{~V} \end{aligned}$ |
| :---: | :---: |
| $\begin{aligned} & \text { IA+, IA-, QA+, QA-, ID+, ID-, QL } \\ & \text { REFIN, COM to GND............. } \end{aligned}$ | REFP, REFN, $\ldots-0.3 \mathrm{~V} \text { to }\left(\mathrm{V}_{D D}+0.3 \mathrm{~V}\right)$ |
| DD0-DD9, SCLK, DIN, $\overline{C S}$, CLK |  |
| DA0-DA7 to OGND | -0.3V to ( $\left.O V_{D D}+0.3 \mathrm{~V}\right)$ |



Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

## ELECTRICAL CHARACTERISTICS

$\left(V_{D D}=3 \mathrm{~V}, \mathrm{OV}_{\mathrm{DD}}=1.8 \mathrm{~V}\right.$, internal reference $(1.024 \mathrm{~V}), \mathrm{CL} \approx 10 \mathrm{pF}$ on all digital outputs, fCLK $=7.5 \mathrm{MHz}, \mathrm{ADC}$ input amplitude $=-0.5 \mathrm{dBFS}$, DAC output amplitude $=0 \mathrm{dBFS}$, differential $A D C$ input, differential DAC output, CREFP $=$ CREFN $=\mathrm{CCOM}=0.33 \mu \mathrm{~F}, \mathrm{Xcvr}$ mode, unless otherwise noted. Typical values are at $\mathrm{T}_{\mathrm{A}}=+25^{\circ} \mathrm{C}$, unless otherwise noted.) (Note 1)

| PARAMETER | SYMBOL | CONDITIONS | MIN | TYP | MAX | UNITS |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| POWER REQUIREMENTS |  |  |  |  |  |  |
| Analog Supply Voltage | VDD |  | 2.7 | 3.0 | 3.3 | V |
| Output Supply Voltage | OVDD |  | 1.8 |  | VDD | V |
| VDD Supply Current |  | ADC operating mode, $\mathrm{fi}=1.875 \mathrm{MHz}$, fCLK $=7.5 \mathrm{MHz}$, DAC operating mode, fout $=$ 620 kHz |  | 7.6 | 9.5 | mA |
|  |  | ADC operating mode, $\mathrm{fiN}=1.875 \mathrm{MHz}$, fCLK $=5.2 \mathrm{MHz}$, DAC operating mode, fout $=$ 620 kHz |  | 6.9 |  |  |
|  |  | ADC operating mode ( Rx ), $\mathrm{f} \mathrm{I}=1.875 \mathrm{MHz}$, $\mathrm{f}_{\mathrm{CLK}}=5.2 \mathrm{MHz}$, DAC off, DAC digital inputs and CLK at zero or OVDD |  | 4.7 |  |  |
|  |  | DAC operating mode (Tx), fout $=620 \mathrm{kHz}$, fCLK $=5.2 \mathrm{MHz}$, ADC off |  | 5.5 |  |  |
|  |  | Standby mode, DAC digital inputs and CLK at zero or OVDD |  |  | 2.0 |  |
|  |  | Idle mode, DAC digital inputs at zero or OVDD, fCLK $=7.5 \mathrm{MHz}$ |  |  | 3.5 |  |
|  |  | Shutdown mode, digital inputs and CLK at zero or OVDD, $\overline{C S}=O V_{D D}$ |  | 1 |  | $\mu \mathrm{A}$ |
| OVDD Supply Current |  | ADC operating mode, $\mathrm{fIN}=1.875 \mathrm{MHz}$, fCLK $=7.5 \mathrm{MHz}$, DAC operating mode, fout $=$ 620 kHz |  | 0.83 |  | mA |
|  |  | Idle mode, DAC digital inputs at zero or OV ${ }_{D D}$, fcLK $=7.5 \mathrm{MHz}$ |  | 7.2 |  | $\mu \mathrm{A}$ |
|  |  | Shutdown mode, DAC digital inputs and CLK at zero or $O V_{D D}, \overline{C S}=O V_{D D}$ |  | 1 |  |  |

# Ultra-Low-Power, High-Dynamic Performance, 7.5Msps Analog Front End 

## ELECTRICAL CHARACTERISTICS (continued)

$\left(V_{D D}=3 \mathrm{~V}, \mathrm{OV}_{D D}=1.8 \mathrm{~V}\right.$, internal reference $(1.024 \mathrm{~V}), \mathrm{CL} \approx 10 \mathrm{pF}$ on all digital outputs, fCLK $=7.5 \mathrm{MHz}, \mathrm{ADC}$ input amplitude $=-0.5 \mathrm{dBFS}$, DAC output amplitude $=0 \mathrm{dBFS}$, differential $A D C$ input, differential DAC output, $\mathrm{C}_{\text {REFP }}=\mathrm{C}_{\text {REFN }}=\mathrm{CCOM}=0.33 \mu \mathrm{~F}$, Xcvr mode, unless otherwise noted. Typical values are at $\mathrm{T}_{\mathrm{A}}=+25^{\circ} \mathrm{C}$, unless otherwise noted.) (Note 1)

| PARAMETER | SYMBOL | CONDITIONS | MIN | TYP | MAX | UNITS |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| ADC DC ACCURACY |  |  |  |  |  |  |
| Resolution |  |  | 8 |  |  | Bits |
| Integral Nonlinearity | INL |  |  | $\pm 0.15$ |  | LSB |
| Differential Nonlinearity | DNL | No missing codes over temperature |  | $\pm 0.13$ |  | LSB |
| Offset Error |  | Residual DC offset error |  | $\pm 0.17$ | $\pm 5$ | \%FS |
| Gain Error |  | Includes reference error |  | $\pm 0.71$ | $\pm 5$ | \%FS |
| DC Gain Matching |  |  |  | $\pm 0.03$ | $\pm 0.25$ | dB |
| Offset Matching |  |  |  | $\pm 3$ |  | LSB |
| Gain Temperature Coefficient |  |  |  | $\pm 30$ |  | ppm/ ${ }^{\circ} \mathrm{C}$ |
| Power-Supply Rejection | PSRR | Offset error (VDD $\pm 5 \%$ ) |  | $\pm 0.2$ |  | LSB |
|  |  | Gain error (VDD $\pm 5 \%$ ) |  | $\pm 0.07$ |  |  |
| ADC ANALOG INPUT |  |  |  |  |  |  |
| Input Differential Range | VID | Differential or single-ended inputs |  | $\pm 0.512$ |  | V |
| Input Common-Mode Voltage Range |  |  |  | VDD/2 |  | V |
| Input Impedance | RIN | Switched capacitor load |  | 720 |  | $\mathrm{k} \Omega$ |
|  | CIN |  |  | 5 |  | pF |
| ADC CONVERSION RATE |  |  |  |  |  |  |
| Maximum Clock Frequency | fCLK | (Note 2) |  |  | 7.5 | MHz |
| Data Latency |  | Channel I |  | 5 |  | Clock cycles |
|  |  | Channel Q |  | 5.5 |  |  |
| ADC DYNAMIC CHARACTERISTICS (Note 3) |  |  |  |  |  |  |
| Signal-to-Noise Ratio | SNR | $\mathrm{f} / \mathrm{N}=1.875 \mathrm{MHz}$ | 47 | 48.6 |  | dB |
|  |  | $\mathrm{fIN}=3.75 \mathrm{MHz}$ |  | 48.5 |  |  |
| Signal-to-Noise and Distortion Ratio | SINAD | $\mathrm{fIN}=1.875 \mathrm{MHz}$ | 46.5 | 48.6 |  | dB |
|  |  | $\mathrm{fin}=3.75 \mathrm{MHz}$ |  | 48.5 |  |  |
| Spurious-Free Dynamic Range | SFDR | $\mathrm{fIN}=1.875 \mathrm{MHz}$ | 58 | 69 |  | dBc |
|  |  | $\mathrm{fin}=3.75 \mathrm{MHz}$ |  | 68.3 |  |  |
| Third-Harmonic Distortion | HD3 | $\mathrm{fIN}=1.875 \mathrm{MHz}$ |  | -71 |  | dBc |
|  |  | $\mathrm{fIN}=3.75 \mathrm{MHz}$ |  | -69 |  |  |
| Intermodulation Distortion | IMD | $\begin{aligned} & \mathrm{f}_{1}=2 \mathrm{MHz},-7 \mathrm{dBFS} ; \\ & \mathrm{f}_{2}=2.01 \mathrm{MHz},-7 \mathrm{dBFS} \end{aligned}$ |  | -66 |  | dBc |
| Third-Order Intermodulation Distortion | IM3 | $\begin{aligned} & \mathrm{f}_{1}=2 \mathrm{MHz},-7 \mathrm{dBFS} ; \\ & \mathrm{f}_{2}=2.01 \mathrm{MHz},-7 \mathrm{dBFS} \end{aligned}$ |  | -70 |  | dBc |
| Total Harmonic Distortion | THD | $\mathrm{f} \mathrm{N}=1.875 \mathrm{MHz}$ |  | -68.6 | -57 | dBc |
|  |  | $\mathrm{fin}=3.75 \mathrm{MHz}$ |  | -67 |  |  |

## Ultra-Low-Power, High-Dynamic Performance, 7.5Msps Analog Front End

## ELECTRICAL CHARACTERISTICS (continued)

$\left(V_{D D}=3 V, O V_{D D}=1.8 \mathrm{~V}\right.$, internal reference $(1.024 \mathrm{~V}), C L \approx 10 p F$ on all digital outputs, $f C L K=7.5 \mathrm{MHz}, \mathrm{ADC}$ input amplitude $=-0.5 \mathrm{dBFS}$, DAC output amplitude $=0 \mathrm{dBFS}$, differential $A D C$ input, differential DAC output, $\mathrm{C}_{\text {REFP }}=\mathrm{C}_{\text {REFN }}=\mathrm{CCOM}=0.33 \mu \mathrm{~F}$, XCvr mode, unless otherwise noted. Typical values are at $\mathrm{T}_{\mathrm{A}}=+25^{\circ} \mathrm{C}$, unless otherwise noted.) (Note 1)

| PARAMETER | SYMBOL | CONDITIONS | MIN | TYP |
| :--- | :---: | :--- | :---: | :---: |
| MAX | UNITS |  |  |  |
| Small-Signal Bandwidth | SSBW | AIN $=-20 \mathrm{dBFS}$ | 440 | MHz |
| Large-Signal Bandwidth | FBW | AIN $=-0.5 \mathrm{dBFS}$ | 440 | MHz |
| Aperture Delay |  |  | 3.3 | ns |
| Aperture Jitter |  |  | 2.7 | psRMS |
| Overdrive Recovery Time |  | $1.5 \times$ full-scale input | 2 | ns |

ADC INTERCHANNEL CHARACTERISTICS

| Crosstalk Rejection |  | $\mathrm{finx}=1.875 \mathrm{MHz}$ at $-0.5 \mathrm{dBFS}, \mathrm{fiNY}=$ <br> 0.3 MHz at $-0.5 \mathrm{dBFS}($ Note 5$)$ | -75 | dB |
| :--- | :--- | :--- | :---: | :---: |
| Amplitude Matching |  | $\mathrm{fin}=1.875 \mathrm{MHz}$ at -0.5 dBFS (Note 6) | $\pm 0.03$ | dB |
| Phase Matching |  | $\mathrm{fin}=1.875 \mathrm{MHz}$ at -0.5 dBFS (Note 6) | $\pm 0.03$ | Degrees |

DAC DC ACCURACY

| Resolution | N |  | 10 | Bits |
| :--- | :---: | :--- | :---: | :---: |
| Integral Nonlinearity | INL |  | $\pm 1$ | LSB |
| Differential Nonlinearity | DNL | Guaranteed monotonic | $\pm 0.5$ | LSB |
| Zero-Scale Error |  | Residual DC offset | $\pm 3$ | LSB |
| Full-Scale Error |  | Includes reference error | -35 | LSB |

## DAC DYNAMIC PERFORMANCE

| DAC Conversion Rate |  | (Note 2) |  |  | 7.5 | Msps |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| Noise over Nyquist | $N_{D}$ | fout $=620 \mathrm{kHz}$, fCLK $=7.5 \mathrm{MHz}$ |  | -127 |  | $\mathrm{dBc} / \mathrm{Hz}$ |
| Output-of-Band Noise Power Density | No | fout $=300 \mathrm{kHz}$, fcLK $=5.2 \mathrm{MHz}$, offset $=$ 2 MHz |  | -126 |  | $\mathrm{dBc} / \mathrm{Hz}$ |
| Glitch Impulse |  |  |  | 10 |  | pVs |
| Spurious-Free Dynamic Range | SFDR | $\mathrm{fCLK}=7.5 \mathrm{MHz}$ | fout $=620 \mathrm{kHz}$ | $60 \quad 73$ |  | dBc |
|  |  | $\mathrm{f}_{\text {CLK }}=5.2 \mathrm{MHz}$ | fout $=200 \mathrm{kHz}$ | 71 |  |  |
| Total Harmonic Distortion (to Nyquist) | THD | fCLK $=7.5 \mathrm{MHz}$, fout $=620 \mathrm{kHz}$ |  | -71 | -59 | dB |
| Signal-to-Noise Ratio (to Nyquist) | SNR | $\mathrm{f}_{\text {CLK }}=7.5 \mathrm{MHz}$, fout $=620 \mathrm{kHz}$ |  | 61 |  | dB |

## DAC INTERCHANNEL CHARACTERISTICS

| DAC-to-DAC Output Isolation |  | fouTX, $Y=2 \mathrm{MHz}$, fOUTX, $\mathrm{Y}=2.2 \mathrm{MHz}$ | 80 | dB |
| :--- | :--- | :--- | :---: | :---: |
| Gain Mismatch Between DAC <br> Outputs |  | fout $=620 \mathrm{kHz}, \mathrm{fCLK}=7.5 \mathrm{MHz}$ | 0.05 | dB |
| Phase Mismatch Between DAC <br> Outputs |  | fout $=620 \mathrm{kHz}$, fCLK $=7.5 \mathrm{MHz}$ | $\pm 0.15$ | Degrees |

# Ultra-Low-Power, High-Dynamic Performance, 7.5Msps Analog Front End 

## ELECTRICAL CHARACTERISTICS (continued)

$\left(V_{D D}=3 \mathrm{~V}, \mathrm{OV}_{D D}=1.8 \mathrm{~V}\right.$, internal reference $(1.024 \mathrm{~V}), \mathrm{CL} \approx 10 \mathrm{pF}$ on all digital outputs, fCLK $=7.5 \mathrm{MHz}, \mathrm{ADC}$ input amplitude $=-0.5 \mathrm{dBFS}$, DAC output amplitude $=0 \mathrm{dBFS}$, differential ADC input, differential DAC output, $C_{R E F P}=C_{\text {REFN }}=C C O M=0.33 \mu F$, XCvr mode, unless otherwise noted. Typical values are at $\mathrm{T}_{\mathrm{A}}=+25^{\circ} \mathrm{C}$, unless otherwise noted.) (Note 1)

| PARAMETER | SYMBOL | CONDITIONS | MIN | TYP | MAX | UNITS |
| :--- | :---: | :---: | :---: | :---: | :---: | :---: |
| DAC ANALOG OUTPUT | $V_{\text {FS }}$ |  | $\pm 400$ | mV |  |  |
| Full-Scale Output Voltage |  |  | 1.29 | 1.5 | V |  |
| Output Common-Mode Range |  |  |  |  |  |  |

## ADC-DAC INTERCHANNEL CHARACTERISTICS

| ADC-DAC Isolation |  | ADC $\mathrm{fINI}=\mathrm{f} / \mathrm{NQ}=1.875 \mathrm{MHz}, \mathrm{DAC}$ foUTI $=$ <br> fOUTQ $=620 \mathrm{kHz}, \mathrm{fCLK}=7.5 \mathrm{MHz}$ | 75 | dB |
| :--- | :--- | :--- | :--- | :--- |

## ADC-DAC TIMING CHARACTERISTICS

| CLK Rise to I-ADC Channel-I Output Data Valid | tDOI | Figure 3 (Note 4) | 7.4 | 9 | ns |
| :---: | :---: | :---: | :---: | :---: | :---: |
| CLK Fall to Q-ADC Channel-Q Output Data Valid | tDOQ | Figure 3 (Note 4) | 6.9 | 9 | ns |
| I-DAC Data to CLK Fall Setup Time | tDSI | Figure 4 (Note 4) | 10 |  | ns |
| Q-DAC Data to CLK Rise Setup Time | tDSQ | Figure 4 (Note 4) | 10 |  | ns |
| CLK Fall to I-DAC Data Hold Time | tDHI | Figure 4 (Note 4) | 0 |  | ns |
| CLK rise to Q-DAC Data Hold Time | tDHQ | Figure 4 (Note 4) | 0 |  | ns |
| Clock Duty Cycle |  |  | 50 |  | \% |
| CLK Duty-Cycle Variation |  |  | $\pm 15$ |  | \% |
| Digital Output Rise/Fall Time |  | 20\% to 80\% | 2.6 |  | ns |

SERIAL INTERFACE TIMING CHARACTERISTICS

| Falling Edge of $\overline{\mathrm{CS}}$ to Rising Edge of First SCLK Time | tcss | Figure 5 (Note 4) | 10 | ns |
| :---: | :---: | :---: | :---: | :---: |
| DIN to SCLK Setup Time | tDS | Figure 5 (Note 4) | 10 | ns |
| DIN to SCLK Hold Time | tD | Figure 5 (Note 4) | 0 | ns |
| SCLK Pulse Width High | tch | Figure 5 (Note 4) | 25 | ns |
| SCLK Pulse Width Low | tCL | Figure 5 (Note 4) | 25 | ns |
| SCLK Period | tcP | Figure 5 (Note 4) | 50 | ns |
| SCLK to $\overline{C S}$ Setup Time | tcs | Figure 5 (Note 4) | 0 | ns |
| $\overline{\text { CS High Pulse Width }}$ | tcsw | Figure 5 (Note 4) | 80 | ns |
| MODE RECOVERY TIMING CHARACTERISTICS |  |  |  |  |
| Shutdown Wake-Up Time | tWAKE,SD | From shutdown to Rx mode, Figure 6, ADC settles to within 1dB | 20 | $\mu \mathrm{s}$ |
|  |  | From shutdown to Tx mode, Figure 6, DAC settles to within 10 LSB error. | 40 |  |

## Ultra-Low-Power, High-Dynamic Performance, 7.5Msps Analog Front End

## ELECTRICAL CHARACTERISTICS (continued)

$\left(V_{D D}=3 \mathrm{~V}, \mathrm{OV}_{\mathrm{DD}}=1.8 \mathrm{~V}\right.$, internal reference (1.024V), $\mathrm{CL} \approx 10 \mathrm{pF}$ on all digital outputs, $\mathrm{f} C \mathrm{LK}=7.5 \mathrm{MHz}, \mathrm{ADC}$ input amplitude $=-0.5 \mathrm{dBFS}$, DAC output amplitude $=0 \mathrm{dBFS}$, differential $A D C$ input, differential DAC output, $C_{\text {REFP }}=C_{\text {REFN }}=C C O M=0.33 \mu F$, Xcvr mode, unless otherwise noted. Typical values are at $\mathrm{T}_{\mathrm{A}}=+25^{\circ} \mathrm{C}$, unless otherwise noted.) (Note 1)

| PARAMETER | SYMBOL | CONDITIONS | MIN | TYP | MAX | UNITS |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| Idle Wake-Up Time (with CLK) | tWAKE,STO | From idle to Rx mode with CLK present during idle, Figure 6, ADC settles to within 1dB SINAD |  | 10 |  | $\mu \mathrm{s}$ |
|  |  | From idle to Tx mode with CLK present during idle, Figure 6, DAC settles to 10 LSB error |  | 10 |  |  |
| Standby Wake-Up Time | tWAKE,ST1 | From standby to Rx mode, Figure 6, ADC settles to within 1dB SINAD |  | 10 |  | $\mu \mathrm{s}$ |
|  |  | From standby to Tx mode, Figure 6, DAC settles to 10 LSB error |  | 40 |  |  |
| Enable Time from Xcvr or Tx to Rx | tenable, $\mathrm{Rx}$ | ADC settles to within 1 dB SINAD |  | 10 |  | $\mu \mathrm{s}$ |
| Enable Time from Xcvr or Rx to Tx | tenable, Tx | DAC settles to 10 LSB error |  | 10 |  | $\mu \mathrm{s}$ |
| INTERNAL REFERENCE (REFIN = $\mathrm{V}_{\text {DD }}$. V REFPP , VREFN, and $\mathrm{V}_{\text {COM }}$ are generated internally.) |  |  |  |  |  |  |
| Positive Reference |  | VREFP - VCOM |  | 0.256 |  | V |
| Negative Reference |  | VREFN - VCOM |  | -0.256 |  | V |
| Common-Mode Output Voltage | VCOM |  | $\begin{gathered} V_{D D} / 2 \\ -0.15 \end{gathered}$ | VDD/2 | $\begin{aligned} & V_{D D} / 2 \\ & +0.15 \end{aligned}$ | V |
| Differential Reference Output | VREF | VREFP - VREFN | +0.49 | +0.512 | +0.534 | V |
| Differential Reference Temperature Coefficient | REFTC |  |  | $\pm 30$ |  | ppm $/{ }^{\circ} \mathrm{C}$ |
| Maximum REFP/REFN/COM Source Current | IsOURCE |  |  | 2 |  | mA |
| Maximum REFP/REFN/COM Sink Current | ISINK |  |  | 2 |  | mA |
| BUFFERED EXTERNAL REFERENCE (REFIN = 1.024V. VREFP, VREFN, and VCOM are generated internally.) |  |  |  |  |  |  |
| Reference Input | VREFIN |  |  | 1.024 |  | V |
| Differential Reference Output | V DIFF | VREFP - VREFN |  | 0.512 |  | V |
| Common-Mode Output Voltage | VCOM |  |  | VDD $/ 2$ |  | V |
| Maximum REFP/REFN/COM Source Current | IsOURCE |  |  | 2 |  | mA |
| Maximum REFP/REFN/COM Sink Current | ISINK |  |  | 2 |  | mA |
| REFIN Input Resistance |  |  |  | >500 |  | k $\Omega$ |
| REFIN Input Current |  |  |  | -0.7 |  | $\mu \mathrm{A}$ |
| DIGITAL INPUTS (CLK, SCLK, DIN, $\overline{\mathbf{C S}}$, DD0-DD9) |  |  |  |  |  |  |
| Input High Threshold | VINH | DD0-DD9, CLK, SCLK, DIN, $\overline{C S}$ | $\begin{aligned} & 0.7 \times \\ & 0 V_{D D} \end{aligned}$ |  |  | V |

# Ultra-Low-Power, High-Dynamic Performance, 7.5Msps Analog Front End 

## ELECTRICAL CHARACTERISTICS (continued)

$\left(V_{D D}=3 \mathrm{~V}, \mathrm{OV}_{D D}=1.8 \mathrm{~V}\right.$, internal reference $(1.024 \mathrm{~V}), \mathrm{CL} \approx 10 \mathrm{pF}$ on all digital outputs, fCLK $=7.5 \mathrm{MHz}, \mathrm{ADC}$ input amplitude $=-0.5 \mathrm{dBFS}$, DAC output amplitude $=0 \mathrm{dBFS}$, differential ADC input, differential DAC output, $C_{R E F P}=C_{\text {REFN }}=C C O M=0.33 \mu F$, XCvr mode, unless otherwise noted. Typical values are at $\mathrm{T}_{\mathrm{A}}=+25^{\circ} \mathrm{C}$, unless otherwise noted.) (Note 1)

| PARAMETER | SYMBOL | CONDITIONS | MIN | TYP MAX | UNITS |
| :---: | :---: | :---: | :---: | :---: | :---: |
| Input Low Threshold | VINL | DD0-DD9, CLK, SCLK, DIN, $\overline{C S}$ |  | $\begin{aligned} & 0.3 x \\ & O V_{D D} \end{aligned}$ | V |
| Input Leakage | Dİn | DD0-DD9, CLK, SCLK, DIN, $\overline{\mathrm{CS}}=\mathrm{OGND}$ or OVDD |  | $\pm 5$ | $\mu \mathrm{A}$ |
| Input Capacitance | DCIN |  |  | 5 | pF |
| DIGITAL OUTPUTS (DA0-DA7) |  |  |  |  |  |
| Output Voltage Low | VoL | ISINK $=200 \mu \mathrm{~A}$ |  | $\begin{aligned} & 0.2 x \\ & \text { OVDD } \end{aligned}$ | V |
| Output Voltage High | VOH | ISOURCE $=200 \mu \mathrm{~A}$ | $\begin{aligned} & 0.8 \times \\ & \text { OVDD } \end{aligned}$ |  | V |
| Tri-State Leakage Current | ILEAK |  |  | $\pm 5$ | $\mu \mathrm{A}$ |
| Tri-State Output Capacitance | Cout |  |  | 5 | pF |

Note 1: Specifications from $T_{A}=+25^{\circ} \mathrm{C}$ to $+85^{\circ} \mathrm{C}$ are guaranteed by product tests. Specifications from $\mathrm{T}_{\mathrm{A}}=+25^{\circ} \mathrm{C}$ to $-40^{\circ} \mathrm{C}$ are guaranteed by design and characterization.
Note 2: The minimum clock frequency for the MAX5863 is 2 MHz .
Note 3: SNR, SINAD, SFDR, HD3, and THD are based on a differential analog input voltage of -0.5 dBFS referenced to the amplitude of the digital outputs. SINAD and THD are calculated using HD2 through HD6.
Note 4: Guaranteed by design and characterization.
Note 5: Crosstalk rejection is measured by applying a high-frequency test tone to one channel and a low-frequency tone to the second channel. FFTs are performed on each channel. The parameter is specified as the power ratio of the first and second channel FFT test tone bins.
Note 6: Amplitude/phase matching is measured by applying the same signal to each channel, and comparing the magnitude and phase of the fundamental bin on the calculated FFT.

## Typical Operating Characteristics

$\left(V_{D D}=D V_{D D}=3 V, O V_{D D}=1.8 \mathrm{~V}\right.$, internal reference (1.024V), $C_{L} \approx 10 \mathrm{pF}$ on all digital outputs, $f C L K=7.5 \mathrm{MHz} 50 \%$ duty cycle, $A D C$ input amplitude $=-0.5 \mathrm{dBFS}$, DAC output amplitude $=0 \mathrm{dBFS}$, differential ADC input, differential DAC output, CREFP $=$ CREFN $=$ CCom $=0.33 \mu \mathrm{~F}, \mathrm{Xcvr}$ mode, $\mathrm{T}_{\mathrm{A}}=+25^{\circ} \mathrm{C}$, unless otherwise noted.)


## Ultra-Low-Power, High-Dynamic Performance, 7.5Msps Analog Front End

$\left(V_{D D}=D V_{D D}=3 V, O V_{D D}=1.8 \mathrm{~V}\right.$, internal reference (1.024V), $C_{L} \approx 10 \mathrm{pF}$ on all digital outputs, $f_{C L K}=7.5 \mathrm{MHz} 50 \%$ duty cycle, $A D C$ input amplitude $=-0.5 \mathrm{dBFS}$, DAC output amplitude $=0 \mathrm{dBFS}$, differential $A D C$ input, differential DAC output, CreFP $=C_{\text {REFN }}=$ CCOM $=0.33 \mu \mathrm{~F}, \mathrm{Xcvr}$ mode, $\mathrm{T}_{\mathrm{A}}=+25^{\circ} \mathrm{C}$, unless otherwise noted.)


# Ultra-Low-Power, High-Dynamic Performance, 7.5Msps Analog Front End 

## Typical Operating Characteristics (continued)

$\left(V_{D D}=D V_{D D}=3 V, O V_{D D}=1.8 \mathrm{~V}\right.$, internal reference (1.024V), $C_{L} \approx 10 \mathrm{pF}$ on all digital outputs, $\mathrm{f}_{\mathrm{CLK}}=7.5 \mathrm{MHz} 50 \%$ duty cycle, ADC input amplitude $=-0.5 \mathrm{dBFS}$, DAC output amplitude $=0 \mathrm{dBFS}$, differential $A D C$ input, differential DAC output, $\mathrm{C}_{\text {REFP }}=\mathrm{C}_{\text {REFN }}=$ CCOM $=0.33 \mu \mathrm{~F}, \mathrm{Xcvr}$ mode, $\mathrm{T}_{\mathrm{A}}=+25^{\circ} \mathrm{C}$, unless otherwise noted.)


ADC TOTAL HARMONIC DISTORTION vs. SAMPLING RATE


ADC SIGNAL-TO-NOISE AND DISTORTION RATIO vs. CLOCK DUTY CYCLE


ADC SIGNAL-TO-NOISE RATIO vs. SAMPLING RATE


ADC SPURIOUS-FREE DYNAMIC RANGE vs. SAMPLING RATE


ADC TOTAL HARMONIC DISTORTION
vs. CLOCK DUTY CYCLE


ADC SIGNAL-TO-NOISE AND DISTORTION RATIO vs. SAMPLING RATE


ADC SIGNAL-TO-NOISE RATIO vs. CLOCK DUTY CYCLE


ADC SPURIOUS-FREE DYNAMIC RANGE vs. CLOCK DUTY CYCLE


## Ultra-Low-Power, High-Dynamic Performance, 7.5Msps Analog Front End

Typical Operating Characteristics (continued)
$\left(V_{D D}=D V_{D D}=3 V, O V_{D D}=1.8 \mathrm{~V}\right.$, internal reference (1.024V), $C_{L} \approx 10 \mathrm{pF}$ on all digital outputs, $\mathrm{f}_{\mathrm{CLK}}=7.5 \mathrm{MHz} 50 \%$ duty cycle, ADC input amplitude $=-0.5 \mathrm{dBFS}$, DAC output amplitude $=0 \mathrm{dBFS}$, differential ADC input, differential DAC output, CREFP $=$ CREFN $=$ CCOM $=0.33 \mu \mathrm{~F}, \mathrm{X}$ Cvr mode, $\mathrm{T}_{\mathrm{A}}=+25^{\circ} \mathrm{C}$, unless otherwise noted.)


# Ultra-Low-Power, High-Dynamic Performance, 7.5Msps Analog Front End 

## Typical Operating Characteristics (continued)

$\left(V_{D D}=D V_{D D}=3 V, O V_{D D}=1.8 \mathrm{~V}\right.$, internal reference (1.024V), $C_{L} \approx 10 \mathrm{pF}$ on all digital outputs, $\mathrm{f}_{\mathrm{CLK}}=7.5 \mathrm{MHz} 50 \%$ duty cycle, ADC input amplitude $=-0.5 \mathrm{dBFS}$, DAC output amplitude $=0 \mathrm{dBFS}$, differential ADC input, differential DAC output, CREFP $=$ CREFN $=$ CCOM $=0.33 \mu \mathrm{~F}, \mathrm{Xcvr}$ mode, $\mathrm{T}_{\mathrm{A}}=+25^{\circ} \mathrm{C}$, unless otherwise noted.)




REFERENCE OUTPUT VOLTAGE
vs. TEMPERATURE


Ultra-Low-Power, High-Dynamic Performance, 7.5Msps Analog Front End

Pin Description

| PIN | NAME | FUNCTION |
| :---: | :---: | :---: |
| 1 | REFP | Upper Reference Voltage. Bypass with a $0.33 \mu \mathrm{~F}$ capacitor to GND as close to REFP as possible. |
| 2, 8, 43 | $V_{D D}$ | Analog Supply Voltage. Bypass VDD to GND with a combination of a $2.2 \mu \mathrm{~F}$ capacitor in parallel with a $0.1 \mu \mathrm{~F}$ capacitor. |
| 3 | $1 \mathrm{~A}+$ | Channel IA Positive Analog Input. For single-ended operation, connect signal source to IA+. |
| 4 | IA- | Channel IA Negative Analog Input. For single-ended operation, connect IA- to COM. |
| $\begin{gathered} 5,7,12,37 \\ 42 \end{gathered}$ | GND | Analog Ground. Connect all pins to GND ground plane. |
| 6 | CLK | Conversion Clock Input. Clock signal for both ADCs and DACs. |
| 9 | QA- | Channel QA Negative Analog Input. For single-ended operation, connect QA- to COM. |
| 10 | QA+ | Channel QA Positive Analog Input. For single-ended operation, connect signal source to QA+. |
| 11, 33, 39 | VDD | Analog Supply Voltage. Connect to VDD power plane as close to the device as possible. |
| 13-16, 19-22 | DA0-DA7 | ADC Tri-State Digital Output Bits. DA7 is the most significant bit (MSB), and DAO is the least significant bit (LSB). |
| 17 | OGND | Output Driver Ground |
| 18 | OV ${ }_{\text {DD }}$ | Output Driver Power Supply. Supply range from +1.8 V to $\mathrm{V}_{\mathrm{DD}}$ to accommodate most logic levels. Bypass OVDD to OGND with a combination of a $2.2 \mu \mathrm{~F}$ capacitor in parallel with a $0.1 \mu \mathrm{~F}$ capacitor. |
| 23-32 | DD0-DD9 | DAC Digital Input Bits. DD9 is the MSB, and DD0 is the LSB. |
| 34 | DIN | 3-Wire Serial Interface Data Input. Data is latched on the rising edge of the SCLK. |
| 35 | SCLK | 3-Wire Serial Interface Clock Input |
| 36 | $\overline{\mathrm{CS}}$ | 3-Wire Serial Interface Chip Select Input. Apply logic low enables the serial interface. |
| 38 | N.C. | No Connection |
| 40, 41 | QD+, QD- | DAC Channel-QD Differential Voltage Output |
| 44, 45 | ID-, ID+ | DAC Channel-ID Differential Voltage Output |
| 46 | REFIN | Reference Input. Connect to V ${ }_{\text {DD }}$ for internal reference. |
| 47 | COM | Common-Mode Voltage I/O. Bypass COM to GND with a $0.33 \mu \mathrm{~F}$ capacitor. |
| 48 | REFN | Negative Reference I/O. Conversion range is $\pm($ VREFP - VREFN). Bypass REFN to GND with a $0.33 \mu F$ capacitor. |
| - | EP | Exposed Paddle. Exposed paddle is internally connected to GND. Connect EP to the GND plane. |

# Ultra-Low-Power, High-Dynamic Performance, 7.5Msps Analog Front End 

## Detailed Description

The MAX5863 integrates dual 8-bit receive ADCs and dual 10-bit transmit DACs while providing ultra-low power and highest dynamic performance at a conversion rate of 7.5 Msps . The ADCs' analog input amplifiers are fully differential and accept 1VP-p full-scale signals. The DACs' analog outputs are fully differential with $\pm 400 \mathrm{mV}$ full-scale output range at 1.4 V common mode.
The MAX5863 includes a 3-wire serial interface to control operating modes and power management. The serial interface is SPI ${ }^{T M}$ and MICROWIRE ${ }^{\text {TM }}$ compatible. The MAX5863 serial interface selects shutdown, idle, standby, transmit, receive, and transceiver modes.

The MAX5863 can operate in FDD or TDD applications by configuring the device for transmit, receive, or transceiver modes through a 3-wire serial interface. In TDD mode, the digital bus for receive ADC and transmit DAC can be shared to reduce the digital I/O to a single 10-bit parallel multiplexed bus. In FDD mode, the MAX5863 digital I/O can be configured for an 18-bit, parallel multiplexed bus to match the dual 8-bit ADC and dual 10-bit DAC.
The MAX5863 features an internal precision 1.024 V bandgap reference output and is stable over the entire power-supply and temperature ranges.


Figure 1. MAX5863 ADC Internal T/H Circuits
SPI is a trademark of Motorola, Inc. MICROWIRE is a trademark of National Semiconductor Corp.

# Ultra-Low-Power, High-Dynamic Performance, 7.5Msps Analog Front End 

Dual 8-Bit ADC
The ADC uses a seven-stage, fully differential, pipelined architecture that allows for high-speed conversion while minimizing power consumption. Samples taken at the inputs move progressively through the pipeline stages every half-clock cycle. Including the delay through the output latch, the total clock-cycle latency is 5 clock cycles for channel IA and 5.5 clock cycles for channel QA. The ADC's full-scale analog input range is $\pm V_{\text {REF }}$ with a common-mode input range of $\mathrm{V}_{\mathrm{dD}} / 2 \pm 0.2 \mathrm{~V}$. Vref is the difference between Vrefp and Vrefn. See the Reference Configurations section for details.

## Input Track-and-Hold (T/H) Circuits

 Figure 1 displays a simplified functional diagram of the ADC's input T/H circuitry. In track mode, switches S1, S2a, S2b, S4a, S4b, S5a, and S5b are closed. The fully differential circuits sample the input signals onto the two capacitors (C2a and C2b) through switches S4a and S4b. S2a and S2b set the common mode for the amplifier input, and open simultaneously with S 1 , sampling the input waveform. Switches S4a, S4b, S5a, and S5b are then opened before switches S3a and S3b connect capacitors C1a and C1b to the output of the amplifier and switch S4c is closed. The resulting differential voltages are held on capacitors C2a and C2b. The amplifiers charge capacitors C1a and C1b to thesame values originally held on C2a and C2b. These values are then presented to the first-stage quantizers and isolate the pipelines from the fast-changing inputs. The wide input bandwidth T/H amplifiers allow the ADC to track and sample/hold analog inputs of high frequencies (> Nyquist). Both ADC inputs (IA+, QA+, IA-, and QA-) can be driven either differentially or single ended. Match the impedance of IA+ and IA-, as well as QA+ and QA-, and set the common-mode voltage to midsupply (VDD/2) for optimum performance.

ADC Digital Output Data (DAO-DA7) DAO-DA7 are the ADCs' digital logic outputs. The logic level is set by $\mathrm{OV}_{\mathrm{DD}}$ from 1.8 V to $\mathrm{V}_{\mathrm{DD}}$. The digital output coding is offset binary (Table 1, Figure 2). The capacitive load on digital outputs DAO-DA7 should be kept as low as possible ( $<15 \mathrm{pF}$ ) to avoid large digital currents feeding back into the analog portion of the MAX5863 and degrading its dynamic performance. Buffers on the digital outputs isolate them from heavy capacitive loads. Adding $100 \Omega$ resistors in series with the digital outputs close to the MAX5863 helps improve ADC performance. Refer to the MAX5865 EV kit schematic for an example of the digital outputs driving a digital buffer through $100 \Omega$ series resistors.

Table 1. Output Codes vs. Input Voltage

| DIFFERENTIAL INPUT VOLTAGE | DIFFERENTIAL INPUT (LSB) | OFFSET BINARY <br> (DA7-DAO) | OUTPUT DECIMAL CODE |
| :---: | :---: | :---: | :---: |
| $V_{\text {REF }} \times \frac{127}{128}$ | $\begin{gathered} 127 \\ (+ \text { full scale }-1 \text { LSB }) \end{gathered}$ | 11111111 | 255 |
| $V_{\text {REF }} \times \frac{126}{128}$ | $\begin{gathered} 126 \\ (+ \text { full scale - 2LSB) } \end{gathered}$ | 11111110 | 254 |
| $V_{\text {REF }} \times \frac{1}{128}$ | +1 | 10000001 | 129 |
| $V_{\text {REF }} \times \frac{0}{128}$ | $\begin{gathered} 0 \\ \text { (bipolar zero) } \end{gathered}$ | 10000000 | 128 |
| $-\mathrm{V}_{\text {REF }} \times \frac{1}{128}$ | -1 | 01111111 | 127 |
| $-\mathrm{V}_{\text {REF }} \times \frac{127}{128}$ | $\begin{gathered} -127 \\ (- \text { full scale }+1 \text { LSB }) \end{gathered}$ | 00000001 | 1 |
| $-\mathrm{V}_{\text {REF }} \times \frac{128}{128}$ | $\begin{gathered} -128 \\ (-f u l l \\ \text { scale }) \end{gathered}$ | 00000000 | 0 |

# Ultra-Low-Power, High-Dynamic Performance, 7.5Msps Analog Front End 

## ADC System Timing Requirements

Figure 3 shows the relationship between the clock, analog inputs, and the resulting output data. Channel IA $(\mathrm{CHI})$ and channel $\mathrm{QA}(\mathrm{CHQ})$ are simultaneously sampled on the rising edge of the clock signal (CLK) and the resulting data is multiplexed at the DA0-DA7 outputs. CHI data is updated on the rising edge and CHQ

data is updated on the falling edge of the CLK. Including the delay through the output latch, the total clock-cycle latency is 5 clock cycles for CHI and 5.5 clock cycles for CHQ.

Dual 10-Bit DAC
The 10-bit DACs are capable of operating with clock speeds up to 7.5 MHz . The DAC's digital inputs, DD0-DD9, are multiplexed on a single 10-bit bus. The voltage reference determines the data converters' fullscale output voltages. See the Reference Configurations section for setting reference voltage. The DACs utilize a current-array technique with a 1 mA (with 1.024 V reference) full-scale output current driving a $400 \Omega$ internal resistor resulting in a $\pm 400 \mathrm{mV}$ full-scale differential output voltage. The MAX5863 is designed for differential output only and is not intended for single-ended application. The analog outputs are biased at 1.4 V common mode and designed to drive a differential input stage with input impedance $\geq 70 \mathrm{k} \Omega$. This simplifies the analog interface between RF quadrature upconverters and the MAX5863. RF upconverters require a 1.3 V to 1.5 V com-mon-mode bias. The internal DC common-mode bias eliminates discrete level-setting resistors and code-generated level-shifting while preserving the full dynamic range of each transmit DAC. Table 2 shows the output voltage vs. input code.

Figure 2. ADC Transfer Function


Figure 3. ADC System Timing Diagram

Ultra-Low-Power, High-Dynamic Performance, 7.5Msps Analog Front End

Table 2. DAC Output Voltage vs. Input Codes (Internal Reference Mode Vrefdac =
1.024V, External Reference Mode VREFDAC = VREFIN)

| DIFFERENTIAL OUTPUT VOLTAGE | OFFSET BINARY <br> (DDO-DD9) | INPUT DECIMAL CODE |
| :---: | :---: | :---: |
| $\frac{V_{\text {REFDAC }}}{2.56} \times \frac{1023}{1023}$ | 1111111111 | 1023 |
| $\frac{V_{\text {REFDAC }}}{2.56} \times \frac{1021}{1023}$ | 1111111110 | 1022 |
| $\frac{V_{\text {REFDAC }}}{2.56} \times \frac{3}{1023}$ | 1000000001 | 513 |
| $\frac{V_{\text {REFDAC }}}{2.56} \times \frac{1}{1023}$ | 1000000000 | 512 |
| $\frac{-V_{\text {REFDAC }}}{2.56} \times \frac{1}{1023}$ | 0111111111 | 511 |
| $\frac{-V_{\text {REFDAC }}}{2.56} \times \frac{1021}{1023}$ | 0000000001 | 1 |
| $\frac{-V_{\text {REFDAC }}}{2.56} \times \frac{1023}{1023}$ | 00000000 | 0 |



Figure 4. DAC System Timing Diagram

## DAC Timing

Figure 4 shows the relationship between the clock, input data, and analog outputs. Data for the I channel (ID) is latched on the falling edge of the clock signal, and Qchannel (QD) data is latched on the rising edge of the clock signal. Both I and Q outputs are simultaneously updated on the next rising edge of the clock signal.

## 3-Wire Serial Interface and Operation Modes

The 3-wire serial interface controls the MAX5863 operation modes. Upon power-up, the MAX5863 must be programmed to operate in the desired mode. Use the 3 -wire serial interface to program the device for the shutdown, idle, standby, Rx, Tx, or Xcvr mode. An 8-bit data register sets the operation modes as shown in Table 3. The serial interface remains active in all six modes.

# Ultra-Low-Power, High-Dynamic Performance, 7.5Msps Analog Front End 

Table 3. MAX5863 Operation Modes

| FUNCTION | DESCRIPTION | $\begin{gathered} \text { D7 } \\ \text { (MSB) } \end{gathered}$ | D6 | D5 | D4 | D3 | D2 | D1 | D0 |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| Shutdown | Device shutdown. REF is off, ADCs are off, and the ADC bus is tri-stated; DACs are off and the DAC input bus must be set to zero or OVDD. | X | X | X | X | X | 0 | 0 | 0 |
| Idle | REF and CLK are on, ADCs are off, and the ADC bus is tri-stated; DACs are off and the DAC input bus must be set to zero or OVDD. | X | X | X | X | X | 0 | 0 | 1 |
| RX | REF is on, ADCs are on; DACs are off, and the DAC input bus must be set to zero or OVDD. | X | X | X | X | X | 0 | 1 | 0 |
| TX | REF is on, ADCs are off, and the ADC bus is tri-stated; DACs are on. | X | X | X | X | X | 0 | 1 | 1 |
| Xcvr | REF is on, ADCs and DACs are on. | X | X | X | X | X | 1 | 0 | 0 |
| Standby | REF is on, ADCs are off, and the ADC bus is tri-stated; DACs are off and the DAC input bus must be set to zero or OVDD. | X | X | X | X | X | 1 | 0 | 1 |

$x=$ Don't care .

Shutdown mode offers the most dramatic power savings by shutting down all the analog sections of the MAX5863 and placing the ADCs' digital outputs in tristate mode. When the ADCs' outputs transition from tristate to on, the last converted word is placed on the digital outputs. The DACs' digital bus inputs must be zero or OVDD because the bus is not internally pulled up. The DACs' previously stored data is lost when coming out of shutdown mode. The wake-up time from shutdown mode is dominated by the time required to charge the capacitors at REFP, REFN, and COM. In internal reference mode and buffered external reference mode, the wake-up time is typically $40 \mu$ s to enter Xcvr mode, $20 \mu$ s to enter Rx mode, and $40 \mu$ s to enter Tx mode.
In idle mode, the reference and clock distribution circuits are powered, but all other functions are off. The ADCs' outputs are forced to tri-state. The DACs' digital bus inputs must be zero or OVDD, because the bus is not internally pulled up. The wake-up time from the idle mode is $10 \mu$ s required for the ADCs and DACs to be fully operational. When the ADCs' outputs transition from tri-state to on, the last converted word is placed on the digital outputs. In the idle mode, the supply cur-
rent is lowered if the clock input is set to zero or $O V_{D D}$; however, the wake-up time extends to $40 \mu \mathrm{~s}$.
In standby mode, only the ADCs' reference is powered; the rest of the device's functions are off. The pipeline ADCs are off and DAO to DA7 are in tri-state mode. The DACs' digital bus inputs must be zero or OVDD because the bus is not internally pulled up. The wakeup time from standby mode to the Xcvr mode is dominated by the $40 \mu$ s required to activate the pipeline ADCs and DACs. When the ADC outputs transition from tri-state to active, the last converted word is placed on the digital outputs.
The serial digital interface is a standard 3-wire connection compatible with SPI/QSPITM/MICROWIRE/DSP interfaces. Set $\overline{\mathrm{CS}}$ low to enable the serial data loading at DIN. Following $\overline{\mathrm{CS}}$ high-to-low transition, data is shifted synchronously, MSB first, on the rising edge of the serial clock (SCLK). After 8 bits are loaded into the serial input register, data is transferred to the latch. $\overline{\mathrm{CS}}$ must transition high for a minimum of 80 ns before the next write sequence. The SCLK can idle either high or low between transitions. Figure 5 shows the detailed timing diagram of the 3 -wire serial interface.

Ultra-Low-Power, High-Dynamic Performance, 7.5Msps Analog Front End


Figure 5. 3-Wire Serial Interface Timing Diagram


Figure 6. MAX5863 Mode Recovery Timing Diagram

## Mode Recovery Timing

Figure 6 shows the mode recovery timing diagram. TWAKE is the wake-up time when exiting shutdown, idle, or standby mode and entering into Rx, Tx, or Xcvr mode. tENABLE is the recovery time when switching between any Rx, Tx, or Xcvr mode. twake or tenable is the time for the ADC to settle within 1dB of specified SINAD performance and DAC settling to 10 LSB error. tWAKE or tenable times are measured after the 8-bit serial command is latched into the MAX5863 by $\overline{\mathrm{CS}}$ transition high. tENABLE for Xcvr mode is dominated by the DAC wake-up time. The recovery time is $10 \mu \mathrm{~s}$ to switch between Xcvr, Tx, or Rx modes. The recovery time is $40 \mu$ s to switch from shutdown or standby mode to Xcvr mode.

## System Clock Input (CLK)

CLK input is shared by both the ADCs and DACs. It accepts a CMOS-compatible signal level set by OVDD from 1.8 V to VDD. Since the interstage conversion of the device depends on the repeatability of the rising and falling edges of the external clock, use a clock with low jitter and fast rise and fall times (<2ns). Specifically, sampling occurs on the rising edge of the clock signal, requiring this edge to provide the lowest possible jitter. Any significant clock jitter limits the SNR performance of the on-chip ADCs as follows:

$$
\mathrm{SNR}=20 \times \log \left(\frac{1}{2 \times \pi \times \mathrm{f}_{\mathrm{IN}} \times \mathrm{t}_{\mathrm{AJ}}}\right)
$$

# Ultra-Low-Power, High-Dynamic Performance, 7.5Msps Analog Front End 

where $\mathrm{fiN}_{\mathrm{N}}$ represents the analog input frequency and $t_{A J}$ is the time of the clock jitter.
Clock jitter is especially critical for undersampling applications. Consider the clock input as an analog input and route away from any analog input or other digital signal lines. The MAX5863 clock input operates with an OVDD/2 voltage threshold and accepts a $50 \%$ $\pm 15 \%$ duty cycle.

## Reference Configurations

The MAX5863 features an internal precision 1.024 V bandgap reference that is stable over the entire power supply and temperature range. The REFIN input provides two modes of reference operation. The voltage at REFIN (VREFIN) sets reference operation mode (Table 4).
In internal reference mode, connect REFIN to VDD. $V_{\text {REF }}$ is an internally generated 0.512 V . COM, REFP, and REFN are low-impedance outputs with $\mathrm{VCOM}=$ $V_{D D} / 2, V_{\text {Refp }}=V_{D D} / 2+V_{R E F} / 2$, and $V_{\text {REFN }}=V_{D D} / 2-$ $V_{\text {REF/2 }}$. Bypass REFP, REFN, and COM each with a $0.33 \mu \mathrm{~F}$ capacitor. Bypass REFIN to GND with a $0.1 \mu \mathrm{~F}$ capacitor.
In buffered external reference mode, apply 1.024 V $\pm 10 \%$ at REFIN. In this mode, COM, REFP, and REFN are low-impedance outputs with $\mathrm{V}_{\mathrm{COM}}=\mathrm{V}_{\mathrm{dD}} / 2$, $\mathrm{V}_{\text {REFP }}$ $=V_{D D} / 2+V_{\text {REFIN }} / 4$, and $V_{\text {REFN }}=V_{D D} / 2-V_{\text {REFIN }} / 4$. Bypass REFP, REFN, and COM each with a $0.33 \mu \mathrm{~F}$ capacitor. Bypass REFIN to GND with a $0.1 \mu \mathrm{~F}$ capacitor. In this mode, the DAC's full-scale output voltage and common-mode voltage are proportional to the external reference. For example, if the Vrefin is increased by $10 \%$ (max), the DACs' full-scale output voltage is also increased by $10 \%$ or $\pm 440 \mathrm{mV}$, and com-mon-mode voltage increases by $10 \%$.

Table 4. Reference Modes

| V REFIN | REFERENCE MODE |
| :---: | :--- |
| $>0.8 \times \mathrm{V}_{\text {DD }}$ | Internal reference mode. VREF is internally <br> generated to be 0.512V. Bypass REFP, <br> REFN, and COM each with a 0.33 $\mu \mathrm{F}$ <br> capacitor. |
| $1.024 \mathrm{~V} \pm 10 \%$ | Buffered external reference mode. An <br> external 1.024V $\pm 10 \%$ reference voltage <br> is applied to REFIN. VREF is internally <br> generated to be V. VEFIN/2. Bypass REFP, <br> REFN, and COM each with a 0.33 <br> capacitor. Bypass REFIN to GND with a <br> $0.1 \mu \mathrm{~F}$ capacitor. |

## Applications Information

Using Balun Transformer AC-Coupling
An RF transformer (Figure 7) provides an excellent solution to convert a single-ended signal source to a fully differential signal for optimum ADC performance. Connecting the center tap of the transformer to COM provides a VDD/2 DC level shift to the input. A 1:1 transformer can be used, or a step-up transformer can be selected to reduce the drive requirements. In general, the MAX5863 provides better SFDR and THD with fully differential input signals than single-ended signals, especially for high-input frequencies. In differential mode, even-order harmonics are lower as both inputs (IA+, IA-, QA+, QA-) are balanced, and each of the ADC inputs only requires half the signal swing compared to single-ended mode. Figure 8 shows an RF transformer converting the MAX5863 DACs' differential analog outputs to single ended.


Figure 7. Balun-Transformer Coupled Single-Ended to Differential Input Drive for ADCs

# Ultra-Low-Power, High-Dynamic Performance, 7.5Msps Analog Front End 



Figure 8. Balun-Transformer Coupled Differential to SingleEnded Output Drive for DACs


Figure 9. Single-Ended Drive for ADCs

## Using Op-Amp Coupling

Drive the MAX5863 ADCs with op amps when a balun transformer is not available. Figures 9 and 10 show the ADCs being driven by op amps for AC-coupled singleended, and DC-coupled differential applications. Amplifiers such as the MAX4354/MAX4454 provide high speed, high bandwidth, low noise, and low distortion to maintain the input signal integrity. Figure 10 can also be used to interface with the DAC differential analog outputs to provide gain or buffering. The DAC differential analog outputs cannot be used in singleended mode because of the internally generated 1.4 VDC common-mode level. Also, the DAC analog outputs are designed to drive a differential input stage with input impedance $\geq 70 \mathrm{k} \Omega$. If single-ended outputs are desired, use an amplifier to provide differential to single-ended conversion and select an amplifier with proper input common-mode voltage range.

## FDD and TDD Modes

The MAX5863 can be used in diverse applications operating FDD or TDD modes. The MAX5863 operates in Xcvr mode for FDD applications such as WCDMA3GPP (FDD) and 4G technologies. Also, the MAX5863 can switch between Tx and Rx modes for TDD applications like TD-SCDMA, WCDMA-3GPP (TDD), IEEE802.11a/b/g, and IEEE802.16.
In FDD mode, the ADC and DAC operate simultaneously. The ADC bus and DAC bus are dedicated and must be connected in 18-bit parallel (8-bit ADC and 10-bit DAC) to the digital baseband processor. Select Xcvr mode through the 3-wire serial interface and use the conversion clock to latch data. In FDD mode, the MAX5863 uses 21 mW power at f CLK $=5.2 \mathrm{MHz}$. This is the total power of the ADC and DAC operating simultaneously.
In TDD mode, the ADC and DAC operate independently. The ADC and DAC bus are shared and can be connected together, forming a single 10-bit parallel bus to the digital baseband processor. Using the 3-wire serial interface, select between Rx mode to enable the ADC and Tx mode to enable the DAC. When operating in Rx mode, the DAC does not transmit because the core is disabled, and in Tx mode the ADC bus is tri-state. This eliminates any unwanted spurious emissions and prevents bus contention. In TDD mode, the MAX5863 uses 14 mW power in Rx mode at $\mathrm{fCLK}=5.2 \mathrm{MHz}$, and the DAC uses 17 mW in Tx mode.
Figure 11 illustrates the MAX5863 working with the MAX2391 and MAX2395 in TDD mode to provide a complete radio front-end solution. Because the MAX5863 DAC has full differential analog outputs with a common-mode level of 1.4 V , it can interface directly

## Ultra-Low-Power, High-Dynamic Performance, 7.5Msps Analog Front End



Figure 10. ADC DC-Coupled Differential Drive


Figure 11. Typical Application Circuit for TDD mode

# Ultra-Low-Power, High-Dynamic Performance, 7.5Msps Analog Front End 

with RF quadrature modulators while eliminating discrete components and amplifiers used for level-shifting circuits. Also, the DAC's full dynamic range is preserved because the internally generated commonmode level eliminates code-generated level shifting or attenuation due to resistor level shifting. The MAX5863 ADC has 1VP-p full-scale range and accepts input com-mon-mode levels of $\mathrm{V}_{\mathrm{DD}} / 2( \pm 200 \mathrm{mV})$. These features simplify the analog interface between RF quadrature demodulator and ADC while eliminating discrete gain amplifiers and level-shifting components.

## Grounding, Bypassing, and Board Layout

The MAX5863 requires high-speed board layout design techniques. Refer to the MAX5865 EV kit data sheet for a board layout reference. Locate all bypass capacitors as close to the device as possible, preferably on the same side of the board as the device, using surfacemount devices for minimum inductance. Bypass VDD to GND with a $0.1 \mu \mathrm{~F}$ ceramic capacitor in parallel with a $2.2 \mu \mathrm{~F}$ capacitor. Bypass OVDD to OGND with a $0.1 \mu \mathrm{~F}$ ceramic capacitor in parallel with a $2.2 \mu \mathrm{~F}$ capacitor. Bypass REFP, REFN, and COM each to GND with a $0.33 \mu \mathrm{~F}$ ceramic capacitor. Bypass REFIN to GND with a $0.1 \mu \mathrm{~F}$ capacitor.
Multilayer boards with separated ground and power planes yield the highest level of signal integrity. Use a split ground plane arranged to match the physical location of the analog ground (GND) and the digital output driver ground (OGND) on the device package. Connect the MAX5863 exposed backside paddle to the GND plane. Join the two ground planes at a single point


Figure 12a. Integral Nonlinearity
such that the noisy digital ground currents do not interfere with the analog ground plane. The ideal location for this connection can be determined experimentally at a point along the gap between the two ground planes. Make this connection with a low-value, surface-mount resistor ( $1 \Omega$ to $5 \Omega$ ), a ferrite bead, or a direct short. Alternatively, all ground pins could share the same ground plane, if the ground plane is sufficiently isolated from any noisy digital system's ground plane (e.g., downstream output buffer or DSP ground plane).
Route high-speed digital signal traces away from sensitive analog traces. Make sure to isolate the analog input lines to each respective converter to minimize channel-to-channel crosstalk. Keep all signal lines short and free of $90^{\circ}$ turns.

## Dynamic Parameter Definitions ADC and DAC Static Parameter Definitions

 Integral Nonlinearity (INL)Integral nonlinearity is the deviation of the values on an actual transfer function from a straight line. This straight line can be either a best-straight-line fit or a line drawn between the end points of the transfer function, once offset and gain errors have been nullified. The static linearity parameters for the device are measured using the end-point method (DAC Figure 12a).

## Differential Nonlinearity (DNL)

 Differential nonlinearity is the difference between an actual step width and the ideal value of 1 LSB . A DNL error specification of less than 1 LSB guarantees no missing codes (ADC) and a monotonic transfer function (ADC and DAC) (DAC Figure 12b).

Figure 12b. Differential Nonlinearity

# Ultra-Low-Power, High-Dynamic Performance, 7.5Msps Analog Front End 

## ADC Offset Error

Ideally, the midscale transition occurs at 0.5 LSB above midscale. The offset error is the amount of deviation between the measured transition point and the ideal transition point.

DAC Offset Error
Offset error is the difference between the ideal and actual offset point. The offset point is the output value when the digital input is midscale. This error affects all codes by the same amount and usually can be compensated by trimming.

## ADC Gain Error

Ideally, the ADC full-scale transition occurs at 1.5 LSB below full scale. The gain error is the amount of deviation between the measured transition point and the ideal transition point with the offset error removed.

ADC Dynamic Parameter Definitions Aperture Jitter
Figure 13 depicts the aperture jitter ( $\mathrm{t}_{\mathrm{A} J}$ ), which is the sample-to-sample variation in the aperture delay.

## Aperture Delay

Aperture delay ( $\mathrm{t}_{\mathrm{AD}}$ ) is the time defined between the rising edge of the sampling clock and the instant when an actual sample is taken (Figure 13).

Signal-to-Noise Ratio (SNR)
For a waveform perfectly reconstructed from digital samples, the theoretical maximum SNR is the ratio of the full-scale analog input (RMS value) to the RMS quantization error (residual error) and results directly from the ADC's resolution ( N bits):

$$
\mathrm{SNR}(\max )=6.02 \mathrm{~dB} \times \mathrm{N}+1.76 \mathrm{~dB}(\text { in } \mathrm{dB})
$$

In reality, there are other noise sources besides quantization noise: thermal noise, reference noise, clock jitter, etc. SNR is computed by taking the ratio of the RMS signal to the RMS noise. RMS noise includes all spectral components to the Nyquist frequency excluding the fundamental, the first five harmonics, and the DC offset.

Signal-to-Noise Plus Distortion (SINAD)
SINAD is computed by taking the ratio of the RMS signal to the RMS noise. RMS noise includes all spectral components to the Nyquist frequency excluding the fundamental and the DC offset.

## Effective Number of Bits (ENOB)

ENOB specifies the dynamic performance of an ADC at a specific input frequency and sampling rate. An ideal ADC's error consists of quantization noise only. ENOB for a full-scale sinusoidal input waveform is computed from:

$$
\mathrm{ENOB}=(\mathrm{SINAD}-1.76) / 6.02
$$

Total Harmonic Distortion (THD)
THD is typically the ratio of the RMS sum of the first five harmonics of the input signal to the fundamental itself. This is expressed as:

$$
T H D=20 \log \left\lceil\frac{\sqrt{\left(V_{2}^{2}+V_{3}^{2}+V_{4}^{2}+V_{5}^{2}+V_{6}^{2}\right)}}{V_{1}}\right\rceil
$$

where $\mathrm{V}_{1}$ is the fundamental amplitude and $\mathrm{V}_{2}-\mathrm{V}_{6}$ are the amplitudes of the 2nd- through 6th-order harmonics.

Third Harmonic Distortion (HD3)
HD3 is defined as the ratio of the RMS value of the third harmonic component to the fundamental input signal.

Spurious-Free Dynamic Range (SFDR)
SFDR is the ratio expressed in decibels of the RMS amplitude of the fundamental (maximum signal component) to the RMS value of the next-largest spurious component, excluding DC offset.

Intermodulation Distortion (IMD)
IMD is the total power of the intermodulation products relative to the total input power when two tones, $\mathrm{f}_{1}$ and $f_{2}$, are present at the inputs. The intermodulation products are $\left(f_{1} \pm f_{2}\right),\left(2 \times f_{1}\right),\left(2 \times f_{2}\right),\left(2 \times f_{1} \pm f_{2}\right),\left(2 \times f_{2}\right.$ $\left.\pm f_{1}\right)$. The individual input tone levels are at -7 dBFS .

## 3rd-Order Intermodulation (IM3)

IM3 is the power of the worst third-order intermodulation product relative to the input power of either input tone when two tones, $f_{1}$ and $f_{2}$, are present at the inputs. The 3rd-order intermodulation products are ( 2 x $\left.f_{1} \pm f_{2}\right),\left(2 \times f_{2} \pm f_{1}\right)$. The individual input tone levels are at -7 dBFS .


Figure 13. T/H Aperture Timing

## Ultra-Low-Power, High-Dynamic Performance, 7.5Msps Analog Front End

## Power-Supply Rejection

Power-supply rejection is defined as the shift in offset and gain error when the power supply is changed $\pm 5 \%$.

Small-Signal Bandwidth
A small -20dBFS analog input signal is applied to an ADC in such a way that the signal's slew rate does not limit the ADC's performance. The input frequency is then swept up to the point where the amplitude of the digitized conversion result has decreased by 3dB. Note that the $\mathrm{T} / \mathrm{H}$ performance is usually the limiting factor for the small-signal input bandwidth.

## Full-Power Bandwidth

A large -0.5 dBFS analog input signal is applied to an ADC, and the input frequency is swept up to the point where the amplitude of the digitized conversion result has decreased by 3 dB . This point is defined as the fullpower bandwidth frequency.

## DAC Dynamic Parameter Definitions Total Harmonic Distortion

THD is the ratio of the RMS sum of the output harmonics up to the Nyquist frequency divided by the fundamental:

$$
T H D=20 \log \left|\frac{\sqrt{\left(V_{2}^{2}+V_{3}^{2}+\ldots+V_{n}^{2}\right)}}{V_{1}}\right|
$$

where $\mathrm{V}_{1}$ is the fundamental amplitude and $\mathrm{V}_{2}$ through $V_{n}$ are the amplitudes of the 2nd through nth harmonic up to the Nyquist frequency.

Spurious-Free Dynamic Range Spurious-free dynamic range (SFDR) is the ratio of RMS amplitude of the fundamental (maximum signal component) to the RMS value of the next-largest distortion component up to the Nyquist frequency excluding DC.


Chip Information
TRANSISTOR COUNT: 16,765
PROCESS: CMOS

## Ultra-Low-Power, High-Dynamic Performance, 7.5Msps Analog Front End

Package Information
(The package drawing(s) in this data sheet may not reflect the most current specifications. For the latest package outline information, go to www.maxim-ic.com/packages.)


## Ultra-Low-Power, High-Dynamic Performance, 7.5Msps Analog Front End

Package Information (continued)
(The package drawing(s) in this data sheet may not reflect the most current specifications. For the latest package outline information, go to www.maxim-ic.com/packages.)

| COMMON DIMENSIONS |  |  |  |  |  |  |  |  |  |  |  |  |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| PKG | 32L 7x7 |  |  | 44L 7x7 |  |  | 48L 7x7 |  |  | CUSTOM PKG. (T4877-1) 48L 7x7 |  |  |
| SYMBOL | MIN. | NOM. | MAX. | MIN. | NOM. | MAX. | MIN. | NOM. | MAX. | MIN. | NOM. | MAX. |
| A | 0.70 | 0.75 | 0.80 | 0.70 | 0.75 | 0.80 | 0.70 | 0.75 | 0.80 | 0.70 | 0.75 | 0.80 |
| A1 | 0 | 0.02 | 0.05 | 0 | 0.02 | 0.05 | 0 | 0.02 | 0.05 | 0 | 0.02 | 0.05 |
| A2 | 0.20 REF. |  |  | 0.20 REF. |  |  | 0.20 REF. |  |  | 0.20 REF. |  |  |
| b | 0.25 | 0.30 | 0.35 | 0.20 | 0.25 | 0.30 | 0.20 | 0.25 | 0.30 | 0.20 | 0.25 | 0.30 |
| D | 6.90 | 7.00 | 7.10 | 6.90 | 7.00 | 7.10 | 6.90 | 7.00 | 7.10 | 6.90 | 7.00 | 7.10 |
| E | 6,90 | 7.00 | 7.10 | 6.90 | 7.00 | 7.10 | 6.90 | 7.00 | 7.10 | 6,90 | 7.00 | 7.10 |
| e | 0.65 BSC. |  |  | 0.50 BSC . |  |  | 0.50 BSC . |  |  | 0.50 BSC . |  |  |
| k | 0.25 | - | - | 0.25 | - | - | 0.25 | - | - | 0.25 | - | - |
| L | 0.45 | 0.55 | 0.65 | 0.45 | 0.55 | 0.65 | 0.30 | 0.40 | 0.50 | 0.45 | 0.55 | 0.65 |
| N | 32 |  |  | 44 |  |  | 48 |  |  | 44 |  |  |
| ND | 8 |  |  | 11 |  |  | 12 |  |  | 10 |  |  |
| NE | 8 |  |  | 11 |  |  | 12 |  |  | 12 |  |  |


| EXPOSED PAD VARIATIONS |  |  |  |  |  |  |  |  |
| :--- | :--- | :--- | :--- | :--- | :--- | :--- | :--- | :---: |
| PKG. <br> CODES | DEPOPULATED <br> LEADS | D2 |  |  | E2 |  |  | JEDEC <br> MO220 |
|  | MIN. | NOM. | MAX. | MIN. | NOM. | MAX. |  |  |
| REV. C |  |  |  |  |  |  |  |  |$|$

** NOTE: T4877-1 IS A CUSTOM 48L PKG. WITH 4 LEADS DEPOPULATED. TOTAL NUMBER OF LEADS ARE 44.

NOTES:
. DIMENSIONING \& TOLERANCING CONFORM TO ASME Y14.5M-1994.
. ALL DIMENSIONS ARE IN MILLIMETERS. ANGLES ARE IN DEGREES.
3. $N$ IS THE TOTAL NUMBER OF TERMINALS.
4. THE TERMINAL \#1 IDENTIFIER AND TERMINAL NUMBERING CONVENTION SHALL CONFORM TO JESD 95-1 SPP-012. DETAILS OF TERMINAL \#1 IDENTIFIER ARE OPTIONAL, BUT MUST BE LOCATED WITHIN THE ZONE INDICATED. THE TERMINAL \# 1 IDENTIFIER MAY BE EITHER A MOLD OR MARKED FEATURE.
5. DIMENSION b APPLIES TO METALLIZED TERMINAL AND IS MEASURED BETWEEN 0.25 mm AND 0.30 mm FROM TERMINAL TIP.

ND AND NE REFER TO THE NUMBER OF TERMINALS ON EACH D AND E SIDE RESPECTIVELY. DEPOPULATION IS POSSIBLE IN A SYMMETRICAL FASHION.
COPLANARITY APPLIES TO THE EXPOSED HEAT SINK SLUG AS WELL AS THE TERMINALS.
9. DRAWING CONFORMS TO JEDEC MO22O.
10. WARPAGE SHALL NOT EXCEED 0.10 mm .


Maxim cannot assume responsibility for use of any circuitry other than circuitry entirely embodied in a Maxim product. No circuit patent licenses are implied. Maxim reserves the right to change the circuitry and specifications without notice at any time.

## X-ON Electronics

Largest Supplier of Electrical and Electronic Components
Click to view similar products for Analog Front End - AFE category:
Click to view products by Maxim manufacturer:

Other Similar products are found below :
WM8255SEFL ADE9078ACPZ-RL ADA4355ABCZ MAX86176EVKIT\# TC500ACPE MCP3914A1-E/MV ISL51002CQZ-165 AFE5803ZCF TC500CPE AD73311ARSZ-REEL AFE4900YZT AD9961BCPZ ADAS1000-1BCPZ ADAS1000-3BCPZ AD73311LARUZ AD5590BBCZ ADPD1080WBCPZR7 AD73311ARSZ AD73311LARSZ AD73311LARSZ-REEL7 AD73360ARZ AD73360ASUZ AD73360LARZ AD8232ACPZ-R7 AD8456ASTZ AD9081BBPZ-4D4AC AD9675KBCZ AD73360LARZ-REEL AD9822JRSZRL AD9826KRSZ AD9826KRSZRL AD9860BSTZ AD9861BCPZ-50 AD9862BSTZ AD9865BCPZ AD9867BCPZ AD9895KBCZ AD9923ABBCZ AD9942BBCZ AD9943KCPZ AD9945KCPZ AD9945KCPZRL7 AD9949KCPZ AD9963BCPZ AD9972BBCZ AD9974BBCZ AD9977BBCZ AD9978BCPZ ADA4350ARUZ ADAS1000-3BSTZ

